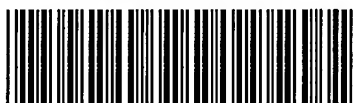


Search Notes



Application/Control No.

10/670,915

Examiner

Devesh Khare

Applicant(s)/Patent under Reexamination

DAIFUKU ET AL.

Art Unit

1623

SEARCHED

Class	Subclass	Date	Examiner
514	395,12, 232.8, 307,336 352,388,50,48		
536	23.7,28.4, 28.1,28.3		
544	106,131 140		
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INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
STIC str search	6/8/06	du
Inventor Search	11/9/06	du
PLVS search	5/17/06	du